# **FAIRCHILD** SEMICONDUCTOR

# **FDMS8090** PowerTrench<sup>®</sup> Power Stage 100 V Symmetric Dual N-Channel MOSFET

# Features

- Max  $r_{DS(on)}$  = 13 m $\Omega$  at V<sub>GS</sub> = 10 V, I<sub>D</sub> = 10 A
- Max  $r_{DS(on)} = 20 \text{ m}\Omega$  at  $V_{GS} = 6 \text{ V}$ ,  $I_D = 8 \text{ A}$
- Low inductance packaging shortens rise/fall times, resulting in lower switching losses
- MOSFET integration enables optimum layout for lower circuit inductance and reduced switch node ringing
- 100% UIL tested
- RoHS Compliant

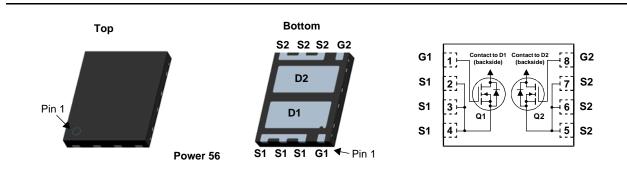


# **General Description**

This device includes two fast switching (Qgd minimized) 100V N-Channel MOSFETs in a dual Power 56 (5 mm X 6 mm MLP) package. The package is enhanced for exceptional thermal performance.

# Applications

- Bridge Topologies
- Synchronous Rectifier Pair
- Motor Drives



# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			100	V	
V <sub>GS</sub>	Gate to Source Voltage			±20	V	
ID	Drain Current -Continuous	T <sub>C</sub> = 25 °C		40		
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	10	Α	
	-Pulsed		(Note 4)	120		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	253	mJ	
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25 °C		59		
	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.2		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C	

# **Thermal Characteristics**

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	2.1	°C/W
$R_{\thetaJA}$	Thermal Resistance, Junction to Ambient (Note 1a	55	C/vv

# Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8090	FDMS8090	Power 56	13 "	12 mm	3000 units

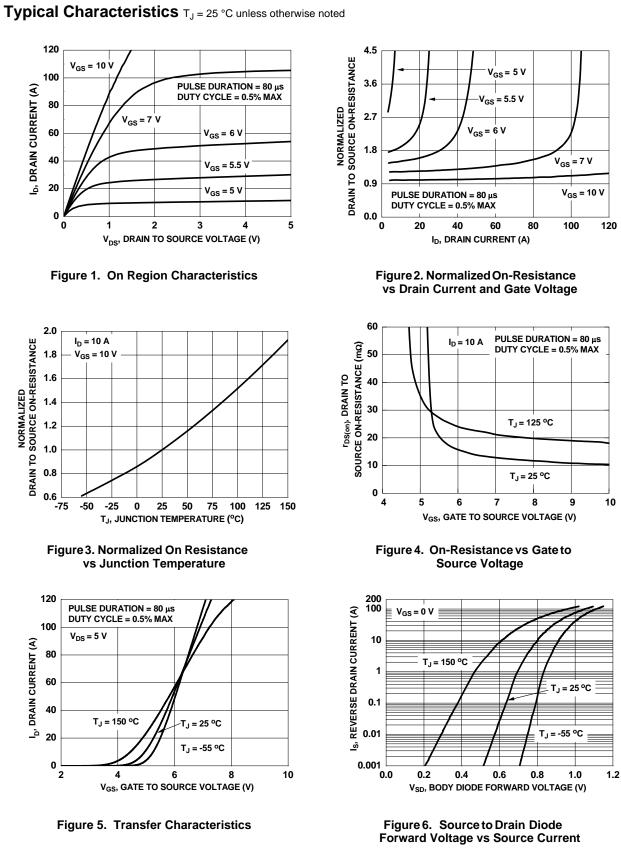
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	Test Conditions	Min	Тур	Max	Units	
cteristics						
Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	100			V	
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		70		mV/°C	
Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μA	
Gate to Source Leakage Current	$V_{GS} = \pm 20 V, V_{DS} = 0 V$			±100	nA	
cteristics						
	$V_{GS} = V_{DS}$ , $I_{D} = 250 \ \mu A$	2.0	3.0	4.0	V	
Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, referenced to 25 °C		-10		mV/°C	
	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		11	13	-	
Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 8 \text{ A}$		15	20	mΩ	
	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A, T <sub>J</sub> = 125 °C		18	20	20	
Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A		24		S	
Characteristics						
			1285	1800	pF	
	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$		301	400	pF	
	f = 1 MHz		16	28	pF	
Gate Resistance		0.1	1.7	3.5	Ω	
Turn-On Delay Time         Rise Time         Turn-Off Delay Time	$V_{DD} = 50 \text{ V, } I_D = 10 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6 \Omega$		10.6 4.6 17.4	21 10 31	ns ns ns	
Fall Time			4	10	ns	
			4.0			
Total Gate Charge	$V_{GS} = 0$ V to 10 V		19	27	nC	
Total Gate Charge Total Gate Charge	$V_{GS} = 0 V \text{ to } 10 V$ $V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 50 V,$		19 10	27 15	nC nC	
	$V_{GS} = 0 V \text{ to } 10 V$ $V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 50 V,$ $I_{D} = 10 A$					
Total Gate Charge	$V_{GS} = 0 V \text{ to } 5 V V_{DD} = 50 V,$		10		nC	
Total Gate ChargeGate to Source ChargeGate to Drain "Miller" Charge	$V_{GS} = 0 V \text{ to } 5 V V_{DD} = 50 V,$		10 6.1		nC nC	
Total Gate Charge         Gate to Source Charge         Gate to Drain "Miller" Charge         urce Diode Characteristics	$V_{GS} = 0 V \text{ to } 5 V$ $V_{DD} = 50 V,$ $I_D = 10 A$		10 6.1		nC nC nC	
Total Gate ChargeGate to Source ChargeGate to Drain "Miller" Charge	$V_{GS} = 0 \ V \ to 5 \ V$ $I_D = 50 \ V,$ $I_D = 10 \ A$ $V_{GS} = 0 \ V, \ I_S = 2 \ A$ (Note 2)		10 6.1 4.1	15	nC nC	
Total Gate Charge         Gate to Source Charge         Gate to Drain "Miller" Charge         urce Diode Characteristics	$V_{GS} = 0 V to 5 V V_{DD} = 50 V,$ $I_{D} = 10 A$ $V_{GS} = 0 V, I_{S} = 2 A $ (Note 2)		10 6.1 4.1 0.7	15	nC nC nC	
	Gate to Source Leakage Current         cteristics         Gate to Source Threshold Voltage         Gate to Source Threshold Voltage         Temperature Coefficient         Static Drain to Source On Resistance         Forward Transconductance         Characteristics         Input Capacitance         Output Capacitance         Gate Resistance         Characteristics         Input Capacitance         Gate Resistance         Characteristics         Turn-On Delay Time         Rise Time	Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ cteristicsGate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250 \mu \text{A}$ Gate to Source Threshold Voltage $I_D = 250 \mu \text{A}$ , referenced to 25 °CGate to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$ Static Drain to Source On Resistance $V_{GS} = 6 \text{ V}, I_D = 8 \text{ A}$ V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125 °CForward Transconductance $V_{DS} = 10 \text{ V}, I_D = 10 \text{ A}$ CharacteristicsInput CapacitanceOutput Capacitance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ Gate ResistanceCharacteristicsTurn-On Delay TimeRise Time $V_{DD} = 50 \text{ V}, I_D = 10 \text{ A}, f = $	Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ cteristicsGate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 250 \mu \text{A}$ 2.0Gate to Source Threshold Voltage Temperature Coefficient $I_D = 250 \mu \text{A}, \text{ referenced to } 25 ^{\circ}\text{C}$ 2.0Static Drain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$ $V_{GS} = 6 \text{ V}, I_D = 8 \text{ A}$ 2.0Forward Transconductance $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125 ^{\circ}\text{C}$ 2.0Forward Transconductance $V_{DS} = 10 \text{ V}, I_D = 10 \text{ A}, T_J = 125 ^{\circ}\text{C}$ 2.0Input Capacitance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ 2.0Gate Resistance0.10.1CharacteristicsTurn-On Delay Time $V_{DD} = 50 \text{ V}, I_D = 10 \text{ A}, T_J = 10 \text{ A}, T_J = 10 \text{ A}, T_J = 10 \text{ A}$	Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ cteristicsGate to Source Threshold Voltage Temperature Coefficient $V_{GS} = V_{DS}, I_D = 250 \ \mu\text{A}$ 2.03.0I_D = 250 \ \mu\text{A}, referenced to 25 °C-10Static Drain to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$ 11V_{GS} = 10 V, I_D = 10 \text{ A}, T_J = 125 °C18Forward Transconductance $V_{DS} = 10 \text{ V}, I_D = 10 \text{ A}$ 24CharacteristicsInput Capacitance Output Capacitance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 10 \text{ A}$ 1285Output Capacitance Gate Resistance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 16 \text{ A}$ 16Gate Resistance0.11.71.7CharacteristicsTurn-On Delay Time Rise Time $V_{DD} = 50 \text{ V}, I_D = 10 \text{ A}, I_$	Gate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ $\pm 100$ cteristics	

2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%.

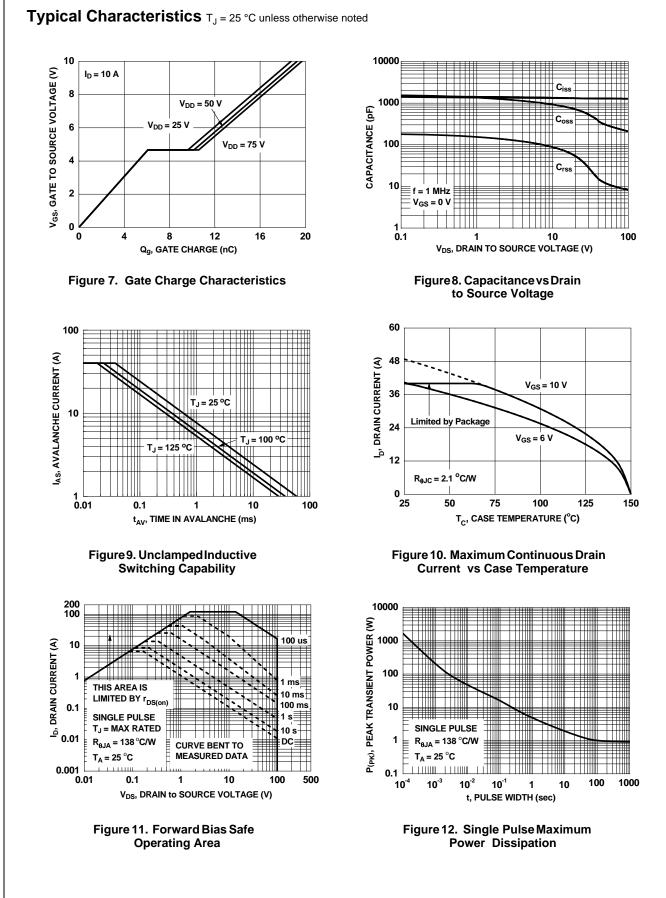
3.  $E_{AS}$  of 253 mJ is based on starting  $T_J$  = 25 °C; N-ch: L = 3 mH,  $I_{AS}$  = 13 A,  $V_{DD}$  = 100 V,  $V_{GS}$  = 10 V. 100% test at L = 0.3 mH,  $I_{AS}$  = 29 A.

4. Pulsed Id limited by junction temperature,td<=10uS. Please refer to SOA curve for more details.



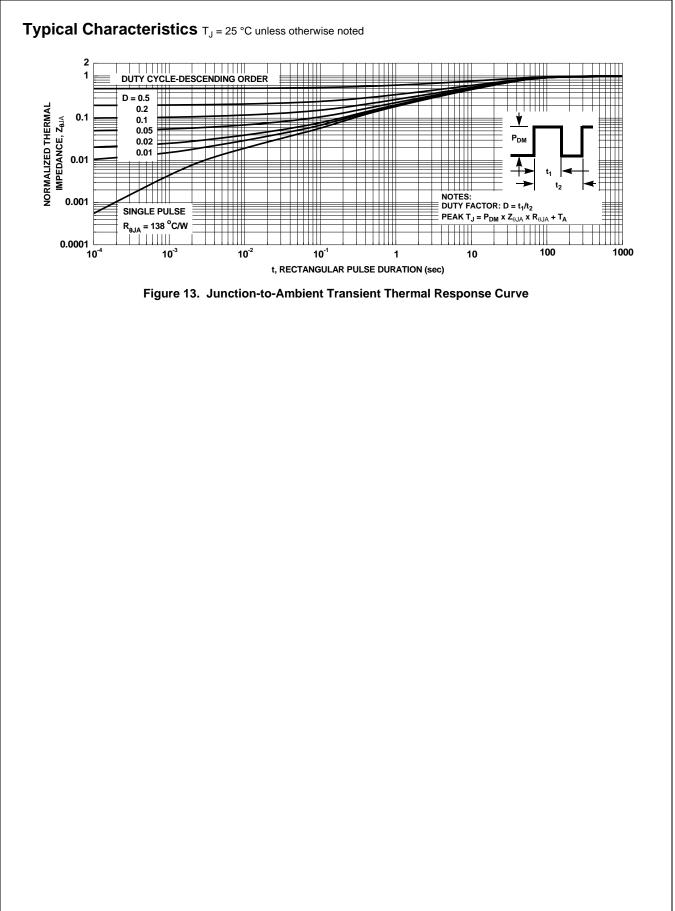
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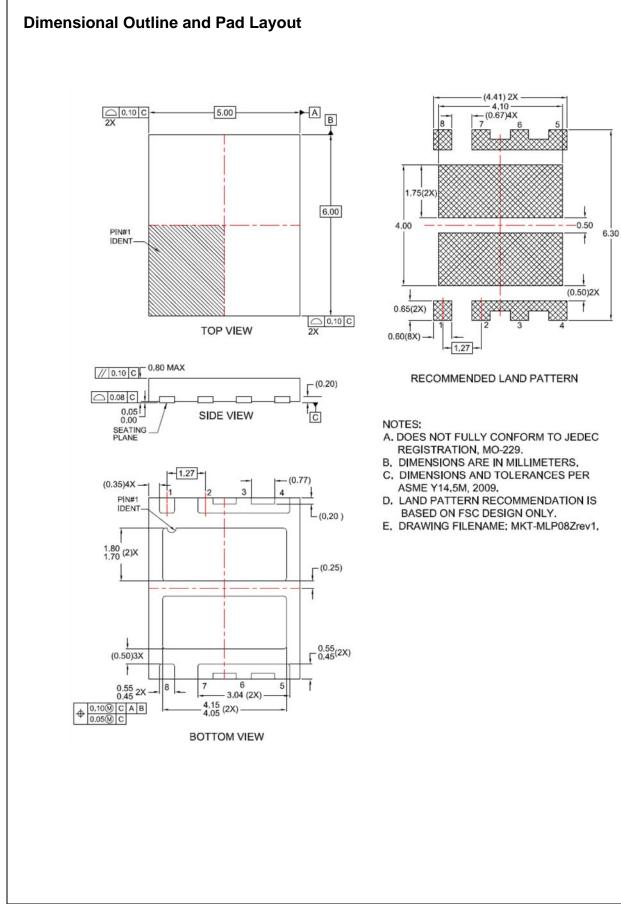
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# FDMS8090 PowerTrench<sup>®</sup> Power Stage

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